

Abstract Submitted
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EUV Spectrometers for Source Development, Characterization and Optimization BRYCE ALLRED, JEFF KEMP, JERSON LOPEZ, LARRY KNIGHT, BYU, SCOTT BERGESON, ALEXANDER SHEVELKO, Lebedev Physical Institute — We report on the development of EUV transmission grating spectrometers. These compact instruments cover an extremely wide spectral range, from 2 to 250 nm, with 0.2 nm resolution and can be absolutely calibrated. They are ideal for characterizing spectral emission from EUV sources. The wide spectral range allows simultaneous measurements of both in-band and out-of-band emission. Spectral measurements from LPP sources on Li and Sn will be presented.

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